

Efficiency Unleashed: Signoff Abstract Model's (SAM) Resource Mastery, Guaranteed QoR and Turbocharged TAT in Static Multi Voltage Verification (SMVV) space

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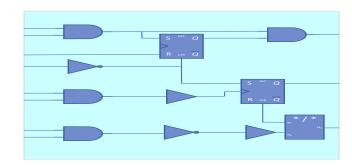


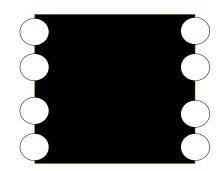
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Traditional Static LP verification Challenges



- As Design sizes grow and advanced power-aware architectures become prevalent, it is crucial to implement early and efficient Static Multi Voltage Verification (SMVV) as a part of convergence and signoff.
- LP checker tool will perform comprehensive SMVV for UPF correctness & implemented power-intent later in • the design flow.
- Traditional SMVV follows 2 approaches:
 - Full Flat Flow
 - Full Low Power (LP) coverage.
 - High resource requirement.
 - High Turn Around Time (TAT).
 - Black Box Flow
 - Lesser TAT and resource requirement.
 - Less coverage.
 - LP information lost.

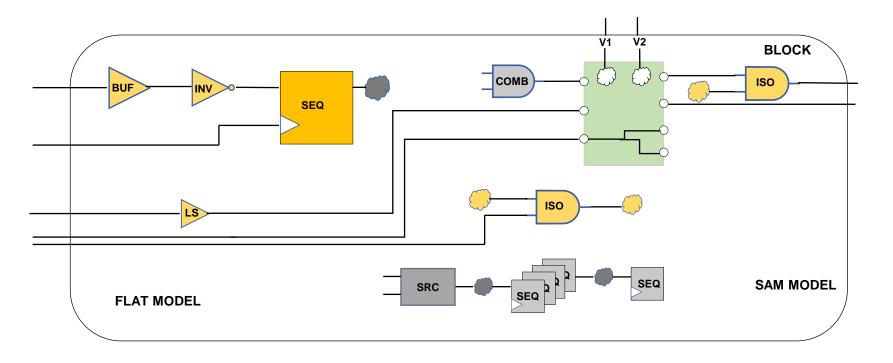




Need a robust solution overcoming TAT and resource upshift while maintaining LP coverage intact. SNUG INDIA 2024 3

What is SAM Model?

- snug
- Signoff Abstract Model (SAM) is a leaner retained model created out of original netlist taking into consideration the UPF constructs.
- The main retention logic principle it follows "starting from all Primary Input (PI)/Primary Output (PO) traverses forward/backward, goes through all buffers, inverters, power management cells and stop at first cell/operator which is not part of the aforementioned elements".
- The model goes in hand with flat UPF.



Retention Principle

PI & PO connected cells

All supply nets connected to retained PG pins

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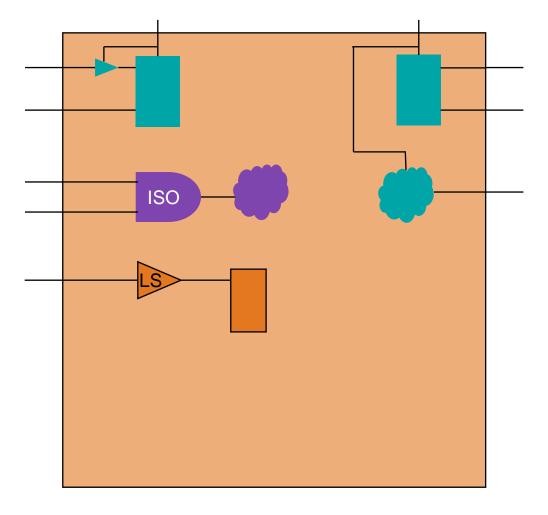
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ISO cells connected to PI/PO

LS cells connected to PI/PO

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Retention Principle (Contd.)

Retention cells connected to PI/PO

LP cells control pin connected to PI/PO

Full crossover path of all input of LP Cells if any connected to PI/PO

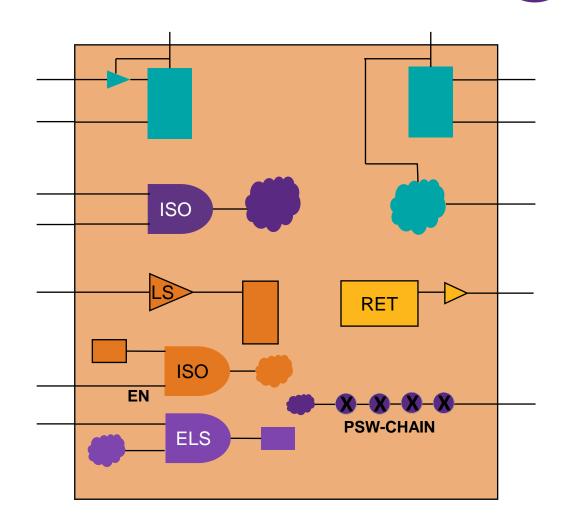


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Full Power switch chain if any input/output connected to PI/PO



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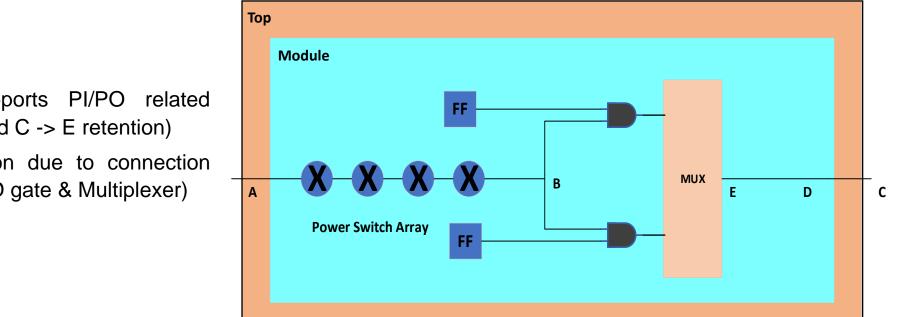
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Incremental SAM Updates



- Single Go Execution-
 - Normal LP Execution with SAM generation.
 - o Unaltered Block QoR.



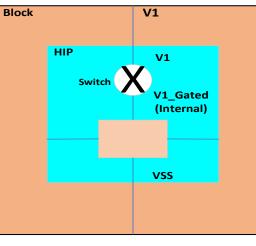


- Power Switch Retention-
 - Retention principle supports PI/PO related connection. (e.g. A->B and C -> E retention)
 - Update to more retention due to connection validation. (e.g. Flop, AND gate & Multiplexer)

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Incremental SAM Updates (Contd.)

- Support for Virtual Supplies-
 - $\circ~$ Virtual supplies present in PST.
 - $\circ~$ PST merging requires these definitions preserved.





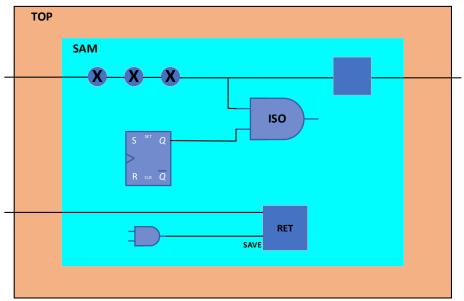
Create_supply_net V1_Gated

Connect_supply_net V1_Gataed -ports HIP/V1_Gated

Add_port_State .. V1_Gated ..

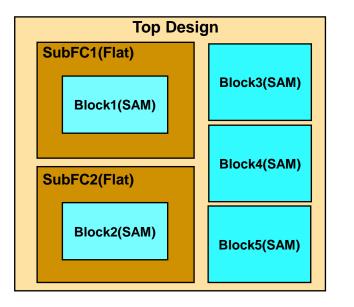
Create_pst .. -supplies { .. V1_Gated ..}

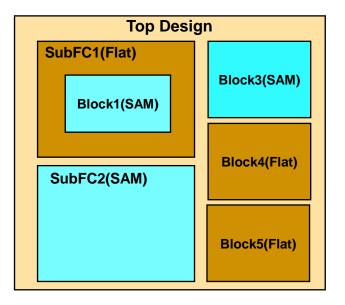
- Extra Logic Retention
 - $\circ~$ Extra retention for control signals.
 - $\circ~$ Control and driving logic preserved.

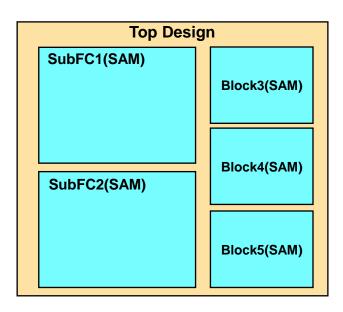


SAM Execution Model

- SAM models can be used in different versatile combinations as per design need.
- Best execution model will always be All blocks are used as SAM in design.







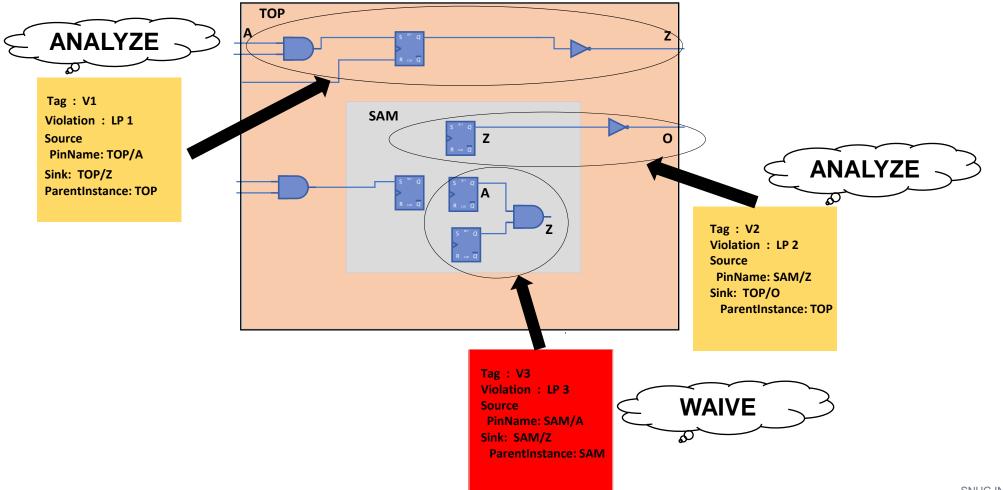


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QoR Flow

• Subtractive QoR flow

- Waiving pure block contained issues.

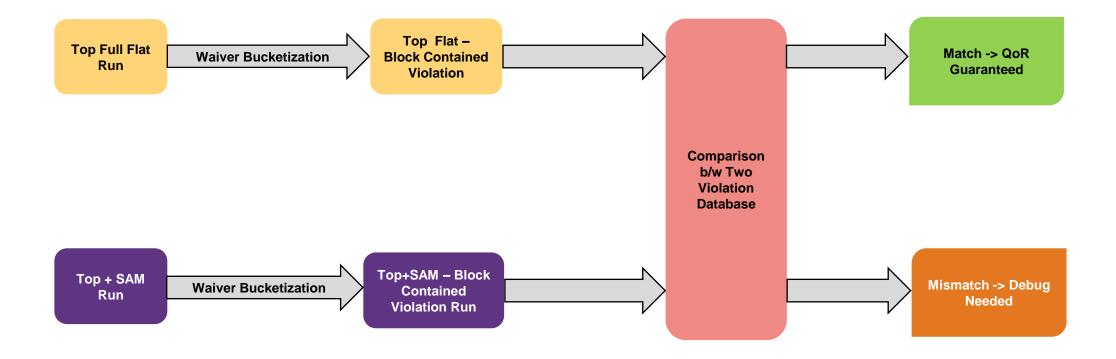




QoR Flow (Contd.)



Paranoia checks can perform comparing with full flat run.

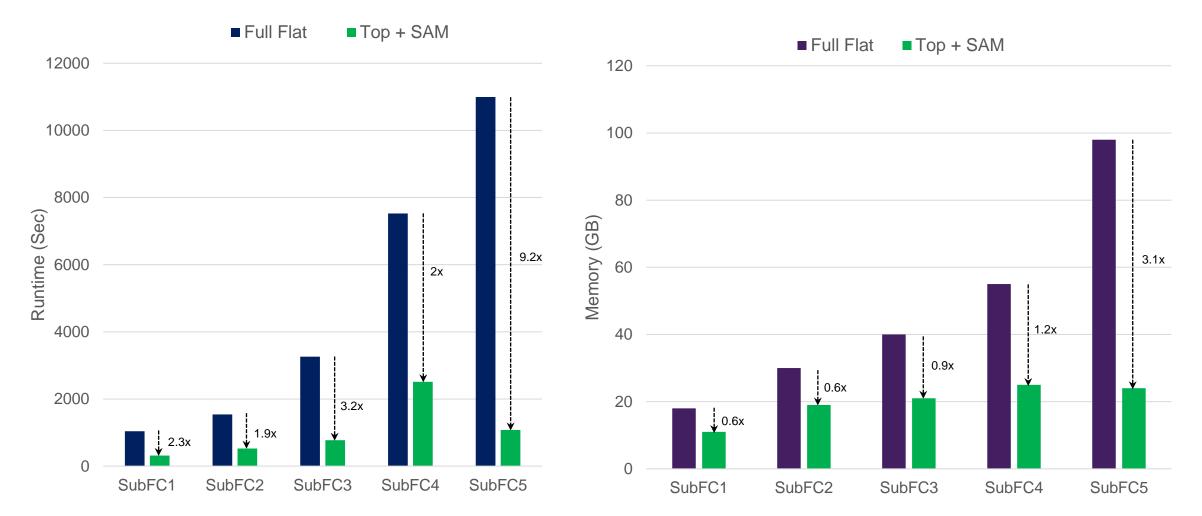


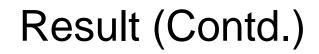


Runtime Comparison



Memory Comparison



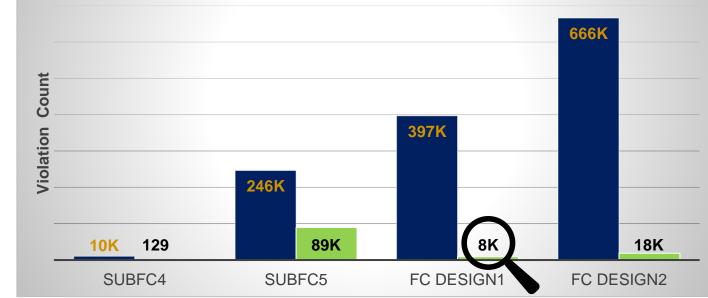




Design	Full Flat Runtime (Hrs)	Top + SAM Runtime (Hrs)	Benefit	Full Flat Memory (GB)	Top + SAM Memory (GB)	Benefit
FC Design1	94.8	10.1	<mark>9.39</mark>	351	98	<mark>3.58</mark>
FC Design2	114	11.45	<mark>9.95</mark>	412	101	4.07

Violation Comparison

Full Flat Top + SAM



Runtime benefit : 3 to 10x

Memory resource benefit : 1.5 to 4x

Debug cycle reduced ~30% due to removal of block contained violations

Conclusion



- The Donut netlist model created by SAM offers both runtime improvement and resource reduction, making it most efficient static LP verification method.
- Guaranteed QoR with a shorter debug cycle accelerates the static LP convergence goals.
- Recommended methodology for all future multi-billion gates design.
- Working with vendor on-

□ On the fly identification and generation of SAM.

□ Further lighter, faster version of SAM.



THANK YOU

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